

WELCOME TO THE 1st FURTHER-FC WORKSHOP!







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i [A/m2]







Further Understanding Related to Transport limitations at High current density towards future ElectRodes for Fuel Cells

Characterization of the CCL structure

Spatial distribution of the materials

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Outline



1.Introduction

- 2. Atomic Force Microscopy
- **3.Electron Microscopy**
- 4.Conclusions







Introduction

Electrodes / CL: Composite of ionomer, Pt catalyst covered mesoporous carbon, and pores

- Reaction at 3-phase boundary Performance & Durability
- electronic conductivity
- ionic conductivity
- gas supply ükü

Uncertainty about ionomer distribution inside the electrode. Quantitative analysis is difficult:

- Small size in the order of few nanometers, depends on humidity and temperature
- 3D-geometry
- Lopez-Haro, Guetaz et al. (CEA): Thickness of 7 nm with electron tomography (HAADF-STEM) at model electrodes
- Morawietz et al. (UES): Thickness measured with adhesion analysis of catalyst layers. Distribution from ~ 4-12 nm.

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Adhesion 200.0 nm Adhesion

Ionomer layer / nm

14

30.0 nm

Position 2 Position 1





Atomic Force Microscopy



Atomic Force Microscopy (AFM)



- AFM uses a small tip (1-25 nm) to scan the surface of a sample to get topographic information and several other properties simultaneously.
- Measurements can be done at ambient conditions and temperature and RH controlled environment









Atomic Force Microscopy (AFM)



- Tapping PeakForce QNM/TUNA-Mode (Bruker Corp.):
- Evaluation and mapping of adhesion force, phase shift, stiffness (DMT modulus), maximal force, dissipation energy, deformation and current.









Atomic Force Microscopy (AFM)



 Using AFM one can discern the different components in the PEMFC and PEMWE electrodes. They consist of catalyst, support materials and (ionomer) binder, the distribution of these components affects MEA performance and degradation rates.



Optical microscope





Analysis of the CCL surface







- Nanomechanics AFM measurement with high resolution tips →
 < 2 nm tip radius
- 3 different phases visible in stiffness, adhesion and deformation channels
- Pt particles may be seen under a layer of ionomer
- Analysis of single Pt Particles difficult



AFM on CCM cross-sections







- Cutting with microtome without embedding
 - Clamped between Polystyrene plates for cutting
 - Measurement of "Blockface"
- Different layers can be analyzed due to different electrical and mechanical properties
- Thickness and material distribution
- Measurement of conductivity possible due to metal coated AFM tips (r_{tip} = 25 nm)



AFM on CCM ion-cut cross-sections



- Ion cutting at -100°C, smooth surface at CL
- Porosity using bearing area \rightarrow 46 % for area of 1 μm^2
- Measurement at ambient conditions gives different thickness of ionomer layers then measured with no humidity.





Analysis of the CCL surface Electronic Conductivity



AFM tip







Electron Microscopy



3D FIB SEM: CCL porosity

3D FIB-SEM principle



Comparison of 3D FIB-SEM images with TEM images

500 nn

3D FIB-SEM



Stack of image acquisition



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FURTHER-FC: Characterization of the CCL structure - Spatial distribution of the materials



3D FIB SEM: CCL porosity



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Segmentation of the 3D image





Public worksh



E-tomography: Pt nanoparticle distribution on the carbon support



Co-funded by the European Union



Challenges of STEM tomography reconstruction due to C density << Pt density:

1. Pt NPs ⇒ HAADF-high angle annular detector to avoid diffraction contrast.

2. C support ⇒ ADF-annular detector to enhance C contrast.

3. Use of advanced algorithm for **3D** image reconstruction that reduces the NP artefacts



Catalyst powder from Tanaka (46.5 wt% Pt on high surface area carbon)

FURTHER-FC: Characterization of the CCL structure - Spatial distribution of the materials



E-tomography: Pt nanoparticle distribution on the carbon support



Co-funded by the European Union



3D image of Pt/C

Outer Pt Inner Pt Carbon

Nanoparticle size histogram

356 Pt NPs = 294 Inner Pt NPs + 62 Outer Pt NPs





Distribution of the ionomer within a real electrodes



Co-funded by the European Union

Impossible to image by high resolution TEM the ionomer in the usual thin MEA cross-section that is embedded in epoxy resin

Development of the cryoultramicrotomy preparation technique by embedding the MEA in a drop of frozen water



M. Salvado et al., J. Power Sources, 2021

Thin slice of cut MEA was successfully deposited on TEM grid



The ionomer thin layer can be observed





Distribution of the ionomer within a real electrodes



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Distribution of the ionomer within a real electrodes



E-tomography for 3D analysis

ADF/STEM tilt series acquisition









- Difficulty in finding an area for high resolution tomography with no C support overlapping for the high tilt angle
- The 3D image reconstruction is still challenging due to the lack of contrast between the ionomer and C support is experiments will be performed on Pt deposited on graphitized carbon



Conclusions



AFM and electron microscopy are complementary techniques for CCL microstructural characterization

• <u>AFM :</u>

- Measurement under different RH conditions
- Measurement of mechanical and electrical properties gives high contrast between Pt/C and ionomer
- Analysis of CCL surface revealed an ionomer layer particularly thick for the high I/C ratio (electrical and mass transport properties are affected)

<u>Electron microscopy</u>

➤ <u>3D FIB/SEM</u>:

- 3D image of the porosity in representative volume (500 μ m³) \Rightarrow to be compared with AFM to evaluate the porosity evolution with RH

≻<u>TEM</u>

- E-tomography : Pt NP distribution of Pt on carbon support
- Resolution is high enough to see thin (>1 2 nm) layers of ionomer (higher resolution than AFM) however 3D is needed but difficult.
- Images revealed some ionomer characteristic features (ionomer filaments, ionomer linking Pt/C agglomerates,

Solution of the ionomer is still under study: improvement of the different techniques and comparison of results are under progress





Thank you for your attention. Your questions are welcome





Public workshop, 06/07/2022, Public workshop, 06/07/2022, DLR/Stuttgart'+ visio Active sites 10⁻¹⁰ m 10⁻⁹ m 10⁻⁷ m

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Coordinator: J. Pauchet (CEA); joel.pauchet@cea.fr FURTHER-FC: Characterization of the CCL structure - Spatial distribution of the materials